

Notice of References Cited

Application/Control No.

10/535,255

Applicant(s)/Patent Under
Reexamination
SADAKIYO ET AL.

Examiner

Lien T. Tran

Art Unit

1794

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,045,847	04-2000	Nakamura et al.	426/508
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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